

Notice of References Cited	Application/Control No. 10/666,304		Applicant(s)/Patent Under Reexamination VANBENSCHOTEN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-4,322,875	04-1982	Brown et al.	24/447
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	E	US-6,106,922	08-2000	Cejka et al.	428/120
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	G	US-6,669,887	12-2003	Hilston et al.	264/173.15
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	I	US-5,260,015	11-1993	Kennedy et al.	264/167
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